## **NC STATE UNIVERSITY**

## Paths of energy changing for electrodes of Li-ion batteries under nonequilibrium process Hongjiang Chen and Hsiao-Ying Shadow Huang Mechanical and Aerospace Engineering, North Carolina State University, Raleigh, NC Introduction and background (d) Li-ion diffusion were (e) Solid solution zone (SSZ) observed **Current Problems of** (c) Electrodes' cracks and Introduction: **Objective:** affected by mechanical during non-equilibrium process<sup>[5][6]</sup> failure<sup>[3]</sup> Li-ion batterv Lithium-ion batteries are critical to Describe and predict electrical deformation<sup>[4]</sup> modern and emerging technologies such (a) Poor power performance potential, capacity, stress and strain as electric vehicles, high-power tools. under high C-rate<sup>[1]</sup> under high C-rate (dis)charging. It stores and release energy by Li-ion's (b) Irreversible capacity loss Present the relation between diffusion between anode and cathode. after cycling and limited stress/strain and solid solution zone lifetime under high C-rate<sup>[2]</sup> Cathod has high (SSZ) during non-equilibrium process Develop approaches to improve Li-Si anode SEM images after (d) 3, ion battery's cyclic life at high C-Li-ion diffusion under FIB (e) 8, (f) 50 and (g-i) 30 cycles. rates doping Scale bar, 20µm (d-h), 3 µm (i). SSZ in electrodes Electrodes with finite deformation Dislocations and electrochemical performance Model Architecture based on Continuum Mechanics and **Dislocation effects for LiFePO4** SSZ in LFP single/multiple particles **Non-Equilibrium Thermodynamics Constitutive models** $\dot{\boldsymbol{\Omega}} = \dot{\boldsymbol{\Omega}} (\lambda, G, \rho, \mathbf{g}, \dot{\mathbf{e}}^{(e)}, \boldsymbol{\sigma}, \dot{\mathbf{e}}, \kappa, x_{(k)}, \boldsymbol{\varepsilon}^{(e)})$ $\mu_{(12)} = \mu_{(12)} (x_{(k)}, \boldsymbol{e}^{(e)}, \rho)$ - zetalF $ds = \sum -\overline{\gamma}^{(l)ij} d\overline{\varepsilon}^{(l)}_{(2)ij} + c_{ij}$ - zetallE - zetalli Momentum equation $\rho \frac{d\mathbf{v}}{dt} = \nabla \cdot \mathbf{p} + \sum_{k=1}^{K} \rho_{(k)} \mathbf{F}_{(k)}$ - YE **Dissipation models** exp - zetalē - zetallE - zetallE Kinematics - zetalil $\frac{\partial \mathcal{E}_{(2)ij}}{\partial \mathcal{E}_{(2)ij}} = \frac{1}{2} \frac{\partial g_{(2)ij}}{\partial \mathcal{E}_{(2)ij}}$ Increase dislocation density -2. ∂t Group B: 3 dislocations Group C: 4 dislocations ∂t Group A: 2 disl Dislocation $\dot{e}_{(2)ij} = \frac{1}{2} \left( \nabla_i v_{(2)j}^L + \nabla_j v_{(2)i}^L \right)$ $r_{+}^{(j)} = C_{+}^{(j)'} \exp \left[ \alpha^{(j)} \beta \sum \mu_{ij} \right]$ $\dot{e}_{(2)ii} = \dot{e}_{ii}^{(e)} + \dot{e}_{ii}^{(p)}$ - YE Mass conservation Dislocation effects $\rho \frac{dx_{(k)}}{dt} + \nabla_i J^i_{(k)} = \sum_i \xi^{(j)}_{(k)} J^{(j)}$ $F \int_{U} J_{M} dV = I$ $\boldsymbol{\sigma}_{DC} = \boldsymbol{\sigma}_{DC} \left( b_x, b_y, r_x, r_y \right) \quad \boldsymbol{u}_{DC} = \boldsymbol{u}_{DC} \left( b_x, b_y, r_x, r_y \right)$ Li diffusion and particle deformation for Tin particle Charging, C-Rate=3, final SOC=0.3 Relavation 600 s -0.2 Λω (V) 0 Ace (V) 0 1 (V CV spectra for differ 4 5 6 7 8 9 hideration density (cm<sup>-2</sup>) ×10<sup>10</sup> 4 6 cation density (cm<sup>-2</sup>) ×10<sup>10</sup> Stress change with increased $\Delta \varphi \langle V \rangle$ CV spectra for different dislocation densities/orientations, scan rate=16mV/s SOC=0 0005 SOC=0 15 SOC=0.3 t = 150 st = 600 s Effective diffusivity Simulated XRD patterns for (a) 5C, (b) 10C and (c) 20C (de)lithiation dislocation density Future Work Simulate whole (dis)charging process and cycling for large deformation of Si anode.

Investigate the detailed influences of dislocation densities on the evolution of SSZ for multi-particles.

· Damage and irreversible capacity loss modeling.

[1] Kang & Ceder, Nature 458, 190-193; [2] J. Xie et al, doi: 10.1149/2.0091503jes; [3] Shi et al, doi: 10.1038/ncomms11886; [4] Saya Takeuchi et al., doi:10.1149/2.1161606jes; [5] Niu et al., dx.doi.org/10.1021/nl501415b; [6] Liu et al., DOI: 10.1126/science.1252817